

IEEE Standards Errata for IEEE Std IEEE Std 1149.1b™-1994 Supplement to IEEE Std 1149.1-1990, IEEE Standard Test Access Port and Boundary-Scan Architecture

Sponsor: Test Technology Standards Committee of the IEEE Computer Society
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The following corrections should be made to the standard:

Page 59, change the second line from the bottom from: "BYPASS (TOPHIP, SETBYP, RUNT, TRIBYP)," & to: "BYPASS (TOPHIP, RUNT)," &

Reason: The SETBYP and TRIBYP instructions were changed to CLAMP and HIGHZ in the INSTRUCTION_OPCODE attribute that starts on page 58. Because they are CLAMP and HIGHZ, it is intrinsically known that they reference the BYPASS register. The SETBYP and TRIBYP names do not appear as opcodes and would thus produce an error.